

Notice of References Cited

Application/Control No.

10/537,319

Applicant(s)/Patent Under
Reexamination
PARK ET AL.

Examiner

Mark Halvorson

Art Unit

1642

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Notice of References Cited

Application/Control No.

11/061,630

Applicant(s)/Patent Under
Reexamination
SADRI, AFSHIN

Examiner

Len Tran

Art Unit

1725

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